

Influence of Geometry on Memristive Behavior of the Domain Wall Spintronic Memristors and its Applications for Measurements

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A spintronic memristor is a device employing the dynamic properties of a propagating magnetic domain wall [1]. Because the dynamics of the domain wall is strongly affected by the device geometry [2], domain wall spintronic memristors (Fig.1) exhibit a geometry dependent memristive behavior. We propose applications of a spintronic memristor in power management [3] and charge sensing. Fig.2a shows a domain wall spintronic memristor (DWSM) in which the derivative of the memristance R with respect to charge q is constant. As it follows from the memristor's constitutive relation [4], such memristors are suited for power monitoring in a circuit as shown in Fig.2b. In addition, memristors with $dR/dq=\text{const}$ are perfectly suited for capacitance sensing, when connected in series with a capacitor. The DWSM shown in Fig.3a has a constant derivative of the memductance G with respect to flux ϕ . It is therefore suited for power monitoring in a system as shown in Fig.3b and also for inductance sensing, when connected in parallel with an inductor. In all cases memristors reduce the problem of measurement to a simple resistance measurement.

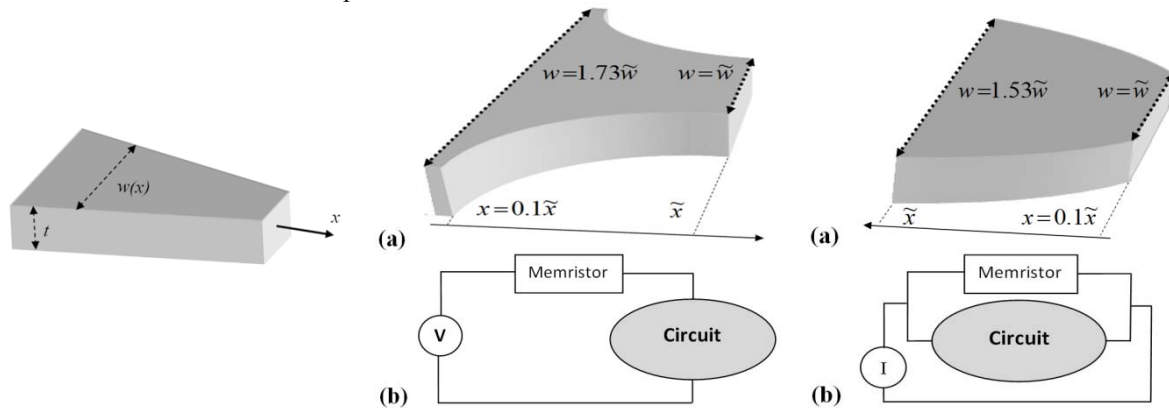


Figure 1. Domain wall spintronic memristor [1]. The constitutive relation is $\phi=A q^{(1-\rho k)/(\rho+1)}$ [1] where q is the charge, ϕ is the flux, A is a constant coefficient, ρ determines the spatial dependence of w as:

$w(x) = \tilde{w}(x/\tilde{x})^\rho$, with \tilde{w} representing w at position \tilde{x} . The parameter k ($=2.2$ [5]) defines the domain wall mobility μ which scales with the aspect ratio $\mu \sim (w/t)^k$.

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References

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